S	earc	h N	otes



Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/052,411	LEE, JONG HAN		
Examiner	Art Unit		
Emmanuel Bayard	2611		

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Class	Subclass	Date	Examiner
375	229	8/16/2007	EB
375	232	8/16/2007	EB
375 ·	233	8/16/2007	EB
375	234	8/16/2007	EB

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	CH NOTES EARCH STRATEG	Y)
	DATE	EXMR
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